

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Bruce Reinhold  
Serial No. :  
Filed : March 22, 2004  
Title : MASS SPECTROSCOPY SYSTEM  
Art Unit : Unknown  
Examiner : Unknown

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

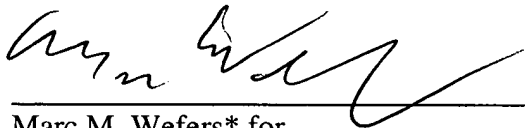
Applicant submits the references listed on the attached form PTO-1449.

This statement is being filed with the application. Accordingly, only copies of foreign patent documents and non-patent literature are enclosed. Please apply any charges or credits to Deposit Account No. 06-1050, referencing Attorney Docket No. 00530-118001.

Respectfully submitted,

Date: \_\_\_\_\_

3/22/04



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**\*See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).**

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CERTIFICATE OF MAILING BY EXPRESS MAIL

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March 22, 2004  
Date of Deposit

Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. <b>00530-118002</b>	Application No.
	Applicant <b>Bruce Reinhold</b>		
	Filing Date <b>March 22, 2004</b>	Group Art Unit	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	RE 34,000	07/21/1992	Syka et al.	250	292	
	AB	4,540,884	09/10/1985	Stafford et al.	250	282	
	AC	4,982,088	01/01/1991	Weitekamp et al.	250	291	
	AD	5,179,278	01/12/1993	Douglas	250	290	
	AE	5,420,425	05/30/1995	Bier et al.	250	292	
	AF	5,420,549	05/30/1995	Prestage	331	94.1	
	AG	6,177,668 B1	01/23/2001	Hager	250	282	
	AH						
	AI						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AJ	WO 01/15201 A2	03/01/2001	WIPO	H01J	49/00		
	AK							
	AL							
	AM							
	AN							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
	AO	
	AP	
	AQ	
	AR	

Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	